

# APPLICATION NOTE

mitsubishi-igbt module

## TENTATIVE

CM100DUS-12

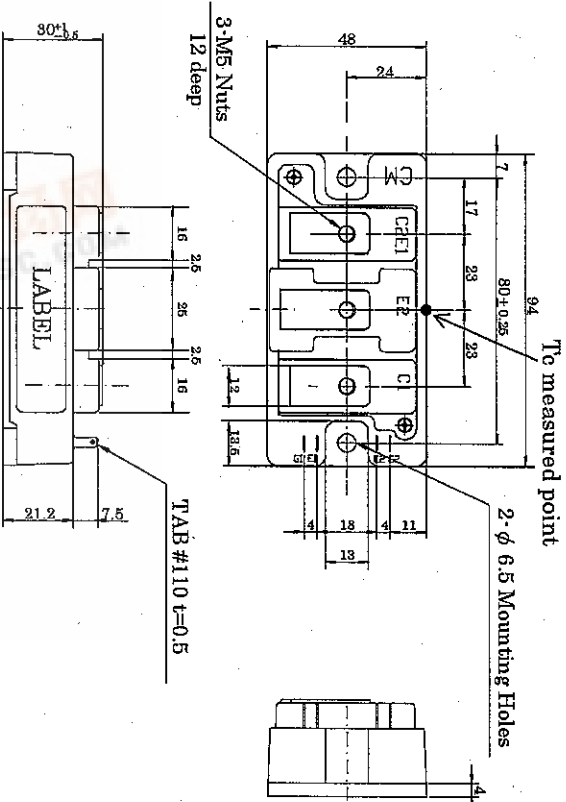
Pre.	NHonda	Rev	A
Apr.	M.Tabata 28-Jan-'99	<i>M. Tabata</i>	

HIGH POWER SWITCHING USE

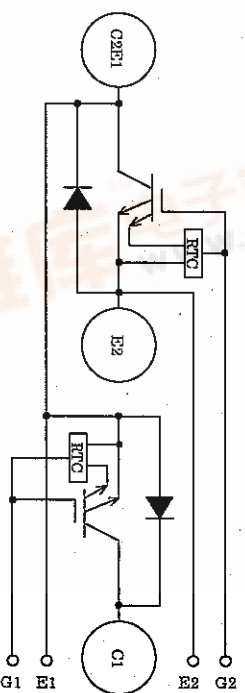
Notice : This is not a final specification. Some parametric limits are subject to change.  
 CM100DUS-12F

### OUTLINE DRAWING

Dimensions in mm



### CIRCUIT DIAGRAM



- I<sub>c</sub>.....100A
- V<sub>GES</sub>.....600V
- Insulated Type
- 2-elements in a pack

### APPLICATION

Welder

### ABSOLUTE MAXIMUM RATINGS (T<sub>v</sub> = 25 °C)

Symbol	Item	Conditions	Ratings	Units
V <sub>GES</sub>	Collector-emitter voltage	G-E Short	600	V
V <sub>GES</sub>	Gate-emitter voltage	C-E Short	±20	V
I <sub>c</sub>	Collector current	T <sub>c</sub> = 25 °C	100	A
I <sub>cm</sub>		Pulse	200	A
I <sub>e</sub>	Emitter current	T <sub>c</sub> = 25 °C	100	A
I <sub>em</sub>		Pulse	200	A
P <sub>c</sub>	Maximum collector dissipation	T <sub>c</sub> = 25 °C	350	W
T <sub>j</sub>	Junction temperature		-40 ~ +150	°C
T <sub>stg</sub>	Storage temperature		-40 ~ +125	°C
Viso	Isolation voltage	Charged part to base plate, AC 1 min.	2500	V
	Torque strength	Main Terminals M 5	2.5 ~ 3.5	N·m
		Mounting holes M 6	3.5 ~ 4.5	N·m
	Weight	Typical value	310	g

查询CM100DUS-12F供应商

捷多邦, 专业PCB打样工厂, 24小时加急出货



ELECTRICAL CHARACTERISTICS (T<sub>j</sub> = 25 °C)

Symbol	Item	Conditions	Min.	Typ.	Max.	Units
I <sub>ces</sub>	Collector cutoff current	V <sub>ce</sub> =V <sub>ces</sub> , V <sub>ge</sub> = 0V	-	-	1	mA
V <sub>ge(th)</sub>	Gate-emitter threshold voltage	I <sub>c</sub> =10mA, V <sub>ce</sub> = 10V	5	6	7	V
I <sub>ges</sub>	Gate leakage current	V <sub>ge</sub> =V <sub>ces</sub> , V <sub>ce</sub> = 0V	-	-	20	μA
V <sub>ce(sat)</sub>	Collector to emitter saturation voltage	T <sub>j</sub> = 25 °C	1.7	2.0	2.7	V
		T <sub>j</sub> = 125 °C	-	1.95	-	
Cies	Input capacitance	V <sub>ce</sub> = 10V	-	-	27	nF
Coes	Output capacitance	V <sub>ge</sub> = 0V	-	-	1.8	
Cres	Reverse transfer capacitance		-	-	1	
Q <sub>g</sub>	Total gate charge	V <sub>cc</sub> = 300V, I <sub>c</sub> = 100A V <sub>ge</sub> = 15V	-	620	-	nC
td(on)	Turn-on delay time	V <sub>cc</sub> =300V, I <sub>c</sub> = 100A	-	-	100	ns
tr	Turn-on rise time	V <sub>ge1</sub> =V <sub>ge2</sub> =15V	-	-	80	
td(off)	Turn-off delay time	R <sub>g</sub> =6.3Ω, Inductive load	-	-	300	
tf	Turn-off fall time	switching operation	-	-	150	
trr	Reverse recovery time	I <sub>e</sub> = 100 A	-	-	150	
Qrr	Reverse recovery charge		-	1.9	-	μC
V <sub>ec</sub>	Emitter-collector voltage	I <sub>e</sub> = 100 A, V <sub>ge</sub> = 0V	-	-	2.6	V
Rth(f-c)Q	Thermal resistance*	IGBT part(1/2 module)	-	-	0.35	°C/W
Rth(f-c)R		FWDI part(1/2 module)	-	-	0.70	
Rth(c-f)	Contact thermal resistance	Case to fin, Thermal compound applied*(1/2 module)	-	0.07	-	
Rth(f-c)Q	Thermal resistance	Tc measured point is, just under the chips	-	0.23*	-	

① I<sub>e</sub>, V<sub>ec</sub>, trr, Qrr & die/dt represent characteristics of the anti-parallel, emitter to collector free-wheel diode (FWDI).

② Pulse width and repetition rate should be such that the device junction temp. (T<sub>j</sub>) dose not exceed T<sub>jmax</sub> rating.

③ Junction temperature (T<sub>j</sub>) should not increase beyond 150°C.

④ Pulse width and repetition rate should be such as to cause negligible temperature rise.

\*1: T<sub>c</sub> measured point is shown in page "1-2".

\*2: Typical value is measured by using Shin-etsu Silicone "G-746".

\*3: If you use this value, Rth(f-a) should be measured just under the chips.